

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D  
Characterisation and Imaging with Ion Beams | (smr 2856)

Contribution ID : 3

Type : **not specified**

## Implementation of External Ion Beam Imaging

*Monday, 26 September 2016 14:00 (1:00)*

### Content

Beam scanning implementation (magnetic deflection + mechanical displacement) Optimization of counting statistics and dwell time/pixel Motorized X/Y/Z sample holder Safety: large view/microscope camera with recording He gas flow Magnetic deflector (PIXE for light elements) Optimal Filters Simultaneous techniques Beam charge monitoring techniques Radiation safety with external beams: rules and procedures

### Summary

**Presenter(s)** : CALLIGARO, Thomas (C2RMF - AGLAE Laboratory, Paris, France)

**Session Classification** : DAY 1